



MICROCHIP

QUALIFICATION PLAN SUMMARY

PCN #: BLAS-15HEYU078

Date:

February 12, 2026

Qualification of MMT as a new final test site and MTAI as a new scan and pack site for SG3526BDW, SG2526BDW, SG2526BDW-TR, SG2526BN, SG3526BDW-TR and SG3526BN catalog part numbers (CPN) available in 18L SOIC (.300in) package and 18L PDIP (.300in) package.

Purpose: Qualification of MMT as a new final test site and MTAI as a new scan and pack site for SG3526BDW, SG2526BDW, SG2526BDW-TR, SG2526BN, SG3526BDW-TR and SG3526BN catalog part numbers (CPN) available in 18L SOIC (.300in) package and 18L PDIP (.300in) package.

CCB No.: 8030.005

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria
Bin and Yield Comparison	Test the same units at existing and destination locations and compare Bin and Yield data.	33	1	≤0.1%
Parametric / Characterization Comparison	Characterize the same units at existing and destination locations and compare data.	33	1	≤10.0%
Correlation Lot Report	Yield at each step and reject analysis between systems. 33 units are tested as lot correlation.	33	1	≤0.1%